N-SIM E
Super Resolution Microscope
**Explore Nano world with Nikon**

N-SIM E is a streamlined, affordable super-resolution system that provides double the resolution of conventional optical microscopes: the same level of superb resolution as Nikon Super Resolution Microscope N-SIM.

**Simple imaging method switching**

The N-SIM E can be simultaneously configured with a confocal microscope system, such as the A1+ or C2+, and imaging methods can be easily switched between super resolution imaging and confocal imaging. A desired location for the SIM image can be specified in a confocal image and acquired in super-resolution.

**Dry objective compatibility**

Dry objectives are now compatible with N-SIM E as well as confocal microscopes, so both confocal imaging and super resolution imaging are available without switching lenses. Low-magnification and wide field-of-view dry lenses enable high resolution observation even at the periphery of sample tissue.
The principle of the Structured Illumination Microscopy

Analytical processing of recorded moiré patterns, produced by overlaying a known high spatial frequency pattern, mathematically restores the sub-resolution structure of a specimen.

Utilization of high spatial frequency laser interference to illuminate sub-resolution structures within a specimen produces moiré fringes, which are captured. These moiré fringes include modulated information of the sub-resolution structure of the specimen. Through image processing, the unknown specimen information can be recovered to achieve resolution beyond the limit of conventional optical microscopes.

Create super-resolution images by processing multiple moiré pattern images

An image of moiré patterns captured in this process includes information of the minute structures within a specimen. Multiple phases and orientations of structured illumination are captured, and the displaced “super-resolution” information is extracted from moiré fringe information. This information is combined mathematically in “Fourier” or aperture space and then transformed back into image space, creating an image at double the conventional resolution limit.

Utilizing high-frequency striped illumination to double the resolution

The capture of high resolution, high spatial frequency information is limited by the Numerical Aperture (NA) of the objectives, and spatial frequencies of structure beyond the optical system aperture are excluded (Fig. A). Illuminating the specimen with high frequency structured illumination, which is multiplied by the unknown structure in the specimen beyond the classical resolution limit, brings the displaced “super-resolution” information within the optical system aperture (Fig. B). When this “super-resolution” information is then mathematically combined with the standard information captured by the objective lens, it results in resolutions equivalent to those captured with objective lenses with approximately double the NA (Fig. C).
Objectives for super-resolution microscopes

The system can be configured with either a 100X oil immersion type, which is suitable for the imaging of fixed samples, or a 60X water immersion type, which is optimal for time-lapse live-cell imaging. The SR (super resolution) objectives have been designed to provide superb optical performance with Nikon's super-resolution microscopes. The adjustment and inspection of lenses using wavefront aberration measurement have been applied to yield optical performances with the lowest possible asymmetric aberration.

Auto correction collar (Option)

This unique, auto correction collar with harmonic drive and automatic correction algorithm, enables perfect alignment of the correction collar of AC series objectives, easily and accurately compensating for changes in temperature, deviation of cover glass thickness, or refractive-index distribution in samples.

3-color multi-laser super-resolution capability

The compact LU-N3-SIM laser unit dedicated for N-SIM E is installed with the three most commonly used wavelength lasers (488/561/640), enabling super-high resolution imaging in multiple colors.

N-SIM analysis software

Image processing, reconstruction and analysis are carried out using the N-SIM E module that resides within Nikon’s universal, cross-platform imaging software NIS-Elements with intuitive, simple operation.

Setting image acquisition

Up to five different laser wavelengths are available. User-customized spectral, z-stack, and time-lapse acquisition settings are automatically managed to allow for a simple workflow from acquisition to image reconstruction. Image reconstruction can be further optimized by modifying reconstruction parameters post-acquisition/offline.

Setting image reconstruction

Auto settings allow the software to automatically select the most appropriate reconstruction parameters for the acquired images. Users can further optimize reconstruction by manually adjusting these parameters.

Reconstruction view

Reconstruction view allows users to preview the results of the selected reconstructed parameters on the current/selected frame, allowing for efficient reconstruction parameter determination.

High-speed reconstruction processing using GPU

High-speed processing using GPU ensures image reconstruction five times faster than that of CPUs, and allows image processing with reduced stress (when using a recommended PC and GPU board).
N-SIM E supports only essential, commonly used excitation wavelengths and imaging modes while providing the same super-resolution images as the N-SIM, making it an obvious choice for individual labs.

Double the resolution of conventional optical microscopes

The N-SIM E utilizes Nikon’s innovative new approach to “structured illumination microscopy” technology. By pairing this powerful technology with Nikon’s renowned CFI Apochromat TIRF series 100X Oil objective (NA 1.49), the N-SIM E nearly doubles the spatial resolution of conventional optical microscopes (to approximately 115 nm*), and enables detailed visualization of the minute intracellular structures and their interactive functions.

*Excited with 488 nm laser, in 3D-SIM mode

Super-resolution image (3D-SIM)  Conventional widefield image

Microtubules in B16 melanoma cell labeled with YFP Objective: CFI Apochromat TIRF 100X Oil (NA 1.49) Image capturing speed: approximately 1 sec/frame (movie) Photographed with the cooperation of: Dr. Yasushi Okada, Laboratory for Cell Polarity Regulation, Quantitative Biology Center, RIKEN

Endoplasmic reticulum (ER) in living HeLa cell labeled with GFP Objective: CFI Apochromat TIRF 100X Oil (NA 1.49) Image capturing speed: approximately 1.5 sec/frame (movie) Photographed with the cooperation of: Dr. Ikuo Wada, Institute of Biomedical Sciences, Fukushima Medical University School of Medicine

Axial super-high resolution imaging with 3D-SIM mode

Two reconstruction methods are available. Slice reconstruction allows axial super-resolution imaging with optical sectioning at 300 nm resolution in live-cell specimens. Optional stack reconstruction can image thicker specimens with higher contrast than slice reconstruction.

Super-resolution image (3D-SIM)  Conventional widefield image

Bacillus subtilis bacterium stained with membrane dye Nile Red (red), and expressing the cell division protein DivIVA fused to GFP (green). The super-resolution microscope allows for accurate localization of the protein during division. Reconstruction method: Slice Photos courtesy of: Drs. Henrik Strahl and Leendert Hamoen, Centre for Bacterial Cell Biology, Newcastle University

Mouse keratinocyte labeled with an antibody against keratin intermediate filaments and stained with an Alexa Fluor 488 conjugated second antibody. Reconstruction method: Stack Photos courtesy of: Dr. Reinhard Windoffer, RWTH Aachen University

Fast 1 sec/frame temporal resolution for super resolution imaging

N-SIM E provides fast imaging performance for Structured Illumination techniques, with a time resolution of approximately 1 sec/frame, which is effective for live-cell imaging.
Specifications

Lateral resolution (FWHM of beads in xy) 115 nm* in 3D-SIM mode
Axial resolution (FWHM of beads in z) 269 nm* in 3D-SIM mode
Image acquisition time Up to 1 sec/frame (3D-SIM)
Imaging mode 3D-SIM
Reconstruction method: slice, stack (option)
Multi-color imaging Up to 3 colors
Compatible Laser LU-N3-SIM laser unit
488 nm, 561 nm, 640 nm
Compatible microscope Motorized inverted microscope ECLIPSE Ti2-E
Perfect Focus System
Motorized XY stage with encoders
Motorized barrier filter wheel
Piezo Z stage (option)

System diagram

TO ENSURE CORRECT USAGE, READ THE CORRESPONDING WARNING MANUALS CAREFULLY BEFORE USING YOUR EQUIPMENT.

Layout

<table>
<thead>
<tr>
<th>Objectives</th>
<th>CFI SR HP Apochromat TIRF 100XC Oil (NA 1.49)</th>
</tr>
</thead>
<tbody>
<tr>
<td>Camera</td>
<td>ORCA-Flash 4.0 sCMOS camera (Hamamatsu Photonics K.K.)</td>
</tr>
<tr>
<td>Software</td>
<td>NIS-Elements AR / NIS-Elements C*</td>
</tr>
</tbody>
</table>

Operating conditions
20 ºC to 28 ºC (± 0.5 ºC)

*These values are measured using 100nm diameter beads excited at 488nm.
Actual resolution is dependent on laser wavelength and optical configuration.
* * Supports slice reconstruction.

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. December 2017 ©2015-17 NIKON CORPORATION

Nikon

NIKON CORPORATION
Shinagawa Intercity Tower C, 2-15-3, Konan, Minato-ku, Tokyo 108-6290, Japan
phone: +81-3-6433-3705 fax: +81-3-6433-3785
http://www.nikon.com/products/microscope-solutions/

ISO 14001 Certified for NIKON CORPORATION

Monitor images are simulated.

Nikon Fluor and Cy are registered trademarks of Thermo Fisher Scientific, Inc.

Company names and product names appearing in this brochure are their registered trademarks or trademarks.

N.B. Export of the products* in this brochure is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedure shall be required in case of export from Japan.

*Products: Hardware and its technical information (including software)

NBS Export of the products* in this brochure is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedure shall be required in case of export from Japan.

*Products: Hardware and its technical information (including software)

Specifications

<table>
<thead>
<tr>
<th>Objective</th>
<th>CFI SR HP Apochromat TIRF 100XC Oil (NA 1.49)</th>
</tr>
</thead>
<tbody>
<tr>
<td>Camera</td>
<td>ORCA-Flash 4.0 sCMOS camera (Hamamatsu Photonics K.K.)</td>
</tr>
<tr>
<td>Software</td>
<td>NIS-Elements AR / NIS-Elements C*</td>
</tr>
</tbody>
</table>

Operating conditions
20 ºC to 28 ºC (± 0.5 ºC)

*These values are measured using 100nm diameter beads excited at 488nm.
Actual resolution is dependent on laser wavelength and optical configuration.
** Supports slice reconstruction.

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. December 2017 ©2015-17 NIKON CORPORATION

Nikon

NIKON CORPORATION
Shinagawa Intercity Tower C, 2-15-3, Konan, Minato-ku, Tokyo 108-6290, Japan
phone: +81-3-6433-3705 fax: +81-3-6433-3785
http://www.nikon.com/products/microscope-solutions/

ISO 14001 Certified for NIKON CORPORATION

Monitor images are simulated.

Nikon Fluor and Cy are registered trademarks of Thermo Fisher Scientific, Inc.

Company names and product names appearing in this brochure are their registered trademarks or trademarks.

N.B. Export of the products* in this brochure is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedure shall be required in case of export from Japan.

*Products: Hardware and its technical information (including software)

NBS Export of the products* in this brochure is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedure shall be required in case of export from Japan.

*Products: Hardware and its technical information (including software)